Assessment of Failure Mechanisms for Thermal Barrier Coatings by Photoluminescence, Electrochemical Impedance and Focused Ion Beam



UNIVERSITY OF CENTRAL FLORIDA

FROM PROMISE TO PROMINENCE CELEBRATING 40 YEARS

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Gas Turbine Needs: Reliable and Durable Thermal Barrier Coatings (TBCs)





Distance



- TBCs Provide Thermal Protection of Hot Components in Advanced Gas Turbine Engines
 - Increase in Performance, Efficiency, Reliability and Maintainability.
 - Reduction Life Cycle Costs.
- Reliable and Durable TBCs Needed as An Integral Part of Component Design.
- Needs Refined Understanding of Failure Mechanisms to Develop a Mechanisms– Based Lifetime Prediction Models.
 - Develop Non-Destructive Evaluation Techniques for Quality Assessment, Life Prediction and Life-Remain Assessment.



Program Objectives

Complimentary Non-Destructive Evaluation (NDE) Techniques:

- Photostimulated Luminescence Spectroscopy (PL).
- Electrochemical Impedance Spectroscopy (EIS).
- State-of-the-Art Microstructural Characterization including:
 ✓ Focused Ion Beam (FIB) In-Situ Lift-Out (INLO).
 - Transmission Electron Microscopy (TEM); Scanning TEM (STEM), Analytical TEM/STEM
- Establish Relationship Between NDE Techniques, Microstructural Development and Failure Mechanisms for TBCs.
- Technology / Knowledge Transfer to Industrial Partners.
- Education for Graduate and Undergraduate Students Through Research in Science, Technology and Professionalism.



Approach: Tasks and Schedule





Accomplishments (1): PL

Stress Relief due to the TGO Cracking Detected Prior to Spallation.

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Stress Relaxation due to Lengthening of the TGO (Racheting) Detected Prior to Spallation).



Accomplishments (2): EIS & TEM/STEM





- Increase in Electrochemical Capacitance of TGO Scale with TGO Thickness.
- Deviation in Trend with the TGO Scale Damage and Electrolyte Exposure.
- FIB-INLO Specimen Preparation for TEM/STEM Microstructural Analysis.



FIB-INLO Specimen Preparation of TBCs and Subsequent TEM/STEM Analysis



Specimen Description* and Testing

TBC System Type	7YSZ Deposition and Thickness (μm)	Bond Coat Type and Thickness (μm)	Superalloy Substrate	Notes
I	EB-PVD; 380	NiCoCrAIY; 200	CM247	Shot-Peened Bondcoat
П	EB-PVD; 150	(Ni,Pt)Al; 50	CMSX-4	As-Coated Bondcoat
III	EB-PVD; 145	(Ni,Pt)Al; 35	Rene'N5	Grit-Blasted Bondcoat
IV	APS; 600	NiCoCrAIY; 180	Haynes 230	APS Bondcoat
V	APS; 240	NiCoCrAIY; 100	MAR-M-509	VPS Bondcoat



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Typical Microstructure of As-Coated TBCs (SEM: Backscatter Electron Images)



I: EBPVD, Shot-Peened NiCoCrAIY Bondcoat



II: EBPVD, As-Coated (Ni,Pt)Al Bondcoat



III: EBPVD, Grit-Blasted (Ni,Pt)Al Bondcoat



Typical Microstructure of As-Coated TBCs (TEM/STEM: Bright & High Angle Annular Dark Field Images)





Thermal Cycling Lifetime / Dwell Time of TBCs



Non-Destructive Evaluation of TBCs During Furnace Thermal Cycling Test by PSLS and EIS



<u>Photostimulated Luminescence:</u> Critical Characteristics of TGO Scale Associated with TBC Failure:

- Phase Constituents in the TGO Scale.
- Residual Stress in the TGO Scale.
- Stress Relief and/or Relaxation Associated with Spallation of TBCs.

Electrochemical Impedance:

- Each AC Circuit Component Corresponds to Physical Parameter of TBC Constituents Quantitatively.
- Measured Electrochemical Impedance is Simulated According to Equivalent AC Circuit.

Luminescence from the TGO with Thermal Cycling {Type II TBC: EB-PVD / As Coated (Ni,Pt)AI / CMSX-4}



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Evolution of Compressive Residual Stress within the TGO with Stress Relief {Type II TBC: EB-PVD / As Coated (Ni,Pt)AI / CMSX-4}



Ampace Statement of Mechanical. Materials and Aerospace Engineer

Microstructural Development During Thermal Cycling {Type II TBC: EB-PVD / As Coated (Ni,Pt)AI / CMSX-4}

1-Hour Thermal Cycling



50-Hour Thermal Cycling



10-Hour Thermal Cycling



- Damages Near the (Ni,Pt)Al Bondcoat Ridges.
- Damages within the TGO (Mixed Oxide Zone) and at the TGO/Bondcoat Interface.

Fractographic Characteristics of TBC Spallation {Type II TBC: EB-PVD / As Coated (Ni,Pt)AI / CMSX-4}

1-Hour Thermal Cycling



50-Hour Thermal Cycling



MPAC

10-Hour Thermal Cycling



- With an Increase in Dwell Time the Fracture Predominantly Occurs at the TGO/Bond coat Interface
- **TGO with Mixed Oxide Zone (MOZ).**
- Grain Boundary Ridges.

Cross-Sectional Microstructure {Type II TBC: EB-PVD / As Coated (Ni,Pt)AI / CMSX-4}



Preferential Oxidation of Grain Boundaries Occurs Significantly During 1-Hour Thermal Cycling, But Not during 10- and 50-Hour Thermal Cycling.



Compressive Residual Stress within the TGO with Stress Relaxation during Thermal Cycling {Type III TBC: EB-PVD / Grit-Blasted (Ni,Pt)AI / Rene'N5}



- Gradual Decrease in the Magnitude of the Compressive Residual Stress in the TGO: Stress Relaxation Associated with Lengthening of TGO and Racheting of TGO/Bondcoat Interface.
- However, such a Relaxation was not Observed during 10- and 50-Hour Thermal Cycling.



Microstructural Development During Thermal Cycling {Type III TBC: EB-PVD / Grit-Blasted (Ni,Pt)AI / Rene'N5}

1-Hour Thermal Cycling



50-Hour Thermal Cycling



10-Hour Thermal Cycling



- No Significant Evidence of Racheting at the TGO/Bondcoat Interface with Increase in Dwell Time.
- Limited Rumpling Observed during 10- and 50-Hour Thermal Cycling.

Fractographic Characteristics of TBC Spallation {Type III TBC: EB-PVD / Grit-Blasted (Ni,Pt)AI / Rene'N5}

1-Hour Thermal Cycling





50- Hour Thermal Cycling



10-Hour Thermal Cycling



- <u>1-Hour Thermal Cycling:</u> Fracture Mostly at the YSZ/TGO Interface; Little within the TGO and at the TGO/Bond Coat Interface.
- <u>10 and 50-Hour Thermal Cycling:</u> Fracture Mostly at the TGO/Bond Coat Interface; Little within the TGO and at the YSZ/TGO Interface.

Cross-Sectional Microstructure from Failed TBCs {Type III TBC: EB-PVD / Grit-Blasted (Ni,Pt)AI / Rene'N5}

1-Hour Thermal Cycles (360 Cycles)





Fracture Mostly at the YSZ/TGO Interface; Racheting.



10-Hour Thermal Cycles (42 Cycles)

15.0kV x1000

15.0kV x500

20um

50-Hour Thermal Cycles (10 Cycles)





Fracture Mostly at the TGO/Bond Coat Interface; No Racheting, but Limited Rumpling.

PL and Microstructural Analysis of Type I TBCs (Type I TBC: EB-PVD / NiCoCrAIY / CM-247)







- PL: The Magnitude of Compressive residual Stress/Standard Deviation Remains Relatively Constant Regardless of Dwell Time.
- Initial Increase in Compressive Residual Stress Potentially due to the Initial Development of the TGO.
- Short Lifetime Due to Internal Oxidation and Premature Formation of Spinel.
- Premature Failure Occurred at the YSZ/TGO Interface.
- Fracture Preferentially Occurred at the TGO/Bond Coat Interface with Longer Dwell Time.



Evolution of EIS with Thermal Cycling of TBCs



10-1

MPAC

0

200

Thermal Cyclic Lifetime (Cycles)

400

600

Jayaraj et al., JOM, in Press. Byeon et al., MSEA, 407 (2005) 213. Y.H. Sohn et al., JOM, 56 (2004) 53. Jayaraj et al., MSEA, 372 (2004) 278. Jayaraj et al., SCT, 177/78 (2004) 140.

Evolution of EIS with Thermal Cycling of TBCs





- Abrupt Increase in C_{TGO} was Not Observed When the Fracture Occurred with the YSZ Coating (No Bond Coat Surface Exposed) for Type IV APS TBCs (with Significant Internal Oxidation of APS NiCoCrAIY Bond Coat).
- A Continuous Increase in C_{TGO} was Observed with Progressive Microcracking in the TGO Scale for Type V APS TBCs.

Jayaraj et al., JOM, in Press.; Byeon et al., MSEA, 407 (2005) 213. Y.H. Sohn et al., JOM, 56 (2004) 53. Jayaraj et al., MSEA, 372 (2004) 278. Jayaraj et al., SCT, 177/78 (2004) 140.

Fractographic Characteristics of APS TBC

TYPE-V: APS TBCs with NiCoCrAIY Bond Coat and MAR-M509



1-Hour Thermal Cycling

TYPE-IV: APS TBCs with APS NiCoCrAIY Bond Coat and HAYNES 230



1-Hour Thermal Cycling



10-Hour Thermal Cycling



10-Hour Thermal Cycling

Fracture Within the YSZ and at the YSZ/TGO Interface for APS TBCs Regardless of Dwell Time.



TGO Capacitance and TGO Thickness



 $\mathbf{C} = \varepsilon_{\mathbf{V}} \bullet \varepsilon \frac{\mathbf{A}}{\mathbf{t}}$

B. Jayaraj et al., Surface and Coatings Technology, 177/8 (2004) 140. Y.H. Sohn et al., Journal of Metals, October (2004) 54.
B. Jayaraj et al., Materials Science and Engineering, A372 (2004) 278.
J. Byeon et al., Materials Science and Engineering A, in Press (2005).



QuickTime™ and a TIFF (Uncompressed) decomp are needed to see this pictu

TEM Specimen Preparation by Focused Ion Beam (FIB) In-Situ Lift-Out (INLO) Technique

TBC Specimens for HR-STEM Investigation Can Be Prepared Routinely and Within 2~3 Hours Regardless of Thermal Cycling History (both As-Coated and Thermally Cycled).





B. Kempshall et al., Thin Solid Films, 466 (2004) 128.

TEM/STEM on Thermally Cycled TBCs



(Ni,Co)(Al,Cr)₂O₄ Controlling Hf Content in the Oxide Stringers
 Oxide Layer Near the Superalloy Substrate Increases Observed as Y₂O₃ on
 YSZ/TGO Interface Lifetime of TBCs by 4X: Several TBC Specimens
 with a Spinel Excellent YSZ/TGO Interface of Different
 Structure and Lattice and Suppression of Rumpling. NiCoCrAly Bond Coats.
 Parameter of 8.0317Å.



Z = Geometry Constant for the TGO; E = Young's Modulus of Al_2O_3 ; v = Poisson's ratio; h = TGO Thickness; G = Strain Energy Release Rate; σ or σ_0 = In-Plane Compressive Stress (due to Thermal Mismatch); \prod = Buckling Index; b = Crack Width.

*A.G.Evans et al, Progress in Materials Science 46 (2001) 505-553; M.C.Shaw Design of Power Electronics Reliability.



Effective Thickness of Oxide (YSZ and TGO) Governing the Failure of TBCs



- The Thickness Governing the Buckling Failure May Include that of TGO and YSZ Combined.
- The Microstructure at or near the YSZ/TGO Interface May Play a Significant Role in Thermo-Mechanical Behavior of Thermal Barrier Coatings During Thermal Cycling.

Partially YSZ

П

Flawed

Easy to Fail

High

Buckling Failure Mechanisms of TBCs* (Incorporating SEM/TEM/STEM Observations)



Cyclic Exposure to High Temperature \rightarrow

*Y.H. Sohn, B. Jayaraj, S. Laxman, B. Franke, J. Byeon, A.M. Karlsson, Journal of Metals, October (2004) 54.



Summary

- Thermal Cycling Lifetime for Each Type of TBC was Determined and Characteristics of Failure was Examined.
 - Rating (e.g., Thermal Cycles or Dwell Time) Among 5-Types of Commercial Production TBCs Remained the Same for 1,10 and 50-Hour Thermal Cycling.
- Great Potential Exists for PL and EIS as Complimentary NDE Techniques for TBCs:
 - PL: Stress Relief of the Highly Stressed TGO due to Subcritical Cracking Prior to Final TBC Spallation.
 - PL: Stress Relaxation of the TGO due to Racheting or Stress-Retention due to No-Racheting.
 - EIS: Subcritical Damage Detection by Electrolyte Penetration.
 - \succ EIS: Correlation between Thickness of the TGO and C_{TGO}.
- TBC Specimens for (S)TEM Can Be Prepared Routinely and Within 2~3 Hours Regardless of Thermal Cycling History:
 - Detailed Microstructural Information on Critical Constituents of TBCs.
 - Refined Understanding of TBC Failure Mechanisms:
 - Importance of YSZ/TGO Interface on the Failure at the TGO/Bond Coat Interface.

Related Highlights From This Program

- 9 Journal Publications (A Few More Coming) and 9 Conference Proceedings.
- 7 Invited Presentations including at ACERS, AVS-ICMCTF, TMS, ASM, ORNL and NIST and 27 Presentations.
- Supported 2 M.S. and 1 Ph.D.:
 - Ms. Barb Franke: Now with Solar Turbines.
 - Mr. Sankar Laxman: Now with Vasologen.
 - Mr. Balaji Jayaraj: Ph.D. Expected in April, 2006.
- Several UG Research Assistants including:
 - Mr. Chris Petorak, Now with Purdue for Ph.D.
 - Ms. Barb Franke, Now with Solar after MS at UCF.
- UTSR Summer Fellows:
 - Ms. Barb Franke, 2003 (Solar) & 2004 (Solar), Now with Solar.
 - Mr. Manny Perez, 2004 (E-M) & 2005 (GE), Now at UCF for Ph.D.
 - Mr. Travis Patterson, 2005 (SPC), Committed for Ph.D. at UCF.
- UCF's M.S. Thesis of 2004 by Mr. Balaji Jayaraj.
- UCF's Distinguished Researcher Award by Sohn, 2005.
- Significant Additional Interaction with IRB Members Through Research Contracts and Collaborations.







